

INPADOCDB (INternational PATent DOCumentation DataBase) contains the bibliographic and family data of patent documents and utility models of 80 patent-issuing organizations including the European Patent Office (EPO) and the World Intellectual Property Organization (WIPO). In addition, the legal status data of 49 patent-issuing organizations are included (36 countries + from 13 countries the nat. phases PCT/EP). Patent citations from 13 countries are also available.

The database corresponds to the EPO Patent Information Resources (combined DOCDB-XMLdata and Inpadoc Legal Status Service).

Note: The accession number can change due to corrections/updates of patent relevant numbers and codes.

SUBJECT COVERAGE

- All areas of science and technology, i.e. all classes of the International Patent Classification

SOURCES

- EPO-Patent Information Resource based on the data supplied by the patent offices (INPADOC/DOCDB Service)
- INPADOC Legal Status Service

FILE DATA

- 1836 to present for patent records
- 1978 to the present for legal status events; legal status from publication data from the beginning
- more than 53 million records (applications) including national patent families with about 65 million published patent applications; 35 million families (07/08)
- about 45 million legal status data in almost 16,2 million records (07/08)
- Updated weekly with 70,000-1.000,000 records and 40,000-180,000 legal status data
- Automatic current-awareness searches (SDIs) may be run weekly or monthly. (Weekly is default)

PRODUCER

European Patent Office
Vienna Sub Office
P.O. Box 90
Austria
Phone: +43 1 52126-0
Fax: +43 1 52126-5491
E-mail: inpadoc.help@epo.org
Copyright Holders

SUPPLIER

FIZ Karlsruhe
P.O. Box 2465
76012 Karlsruhe
Germany
Phone: +49 7247 808-555
Fax: +49 7247 808-131
E-mail: helpdesk@fiz-karlsruhe.de

USER AIDS

- Online Helps (HELP DIRECTORY lists all help messages available)
- STNGUIDE
- Web site: http://www.stn-international.de/training_center/patents/inpadoc_wm.pdf

BIBLIOGRAPHIC SEARCH AND DISPLAY FIELDS

Search Field Name	Search Code	Search Examples	Display Code
Basic Index (contains single words from title (TI) and abstract (AB) fields) 1)	None or /BI	S TUBULAR HEAT EXCHANG? S ALUM? (S) COAT? S ?MAGNET? S ?METHYL?(T)?AMINO? S (DRILLING(W)PROCESS)/AB	AB, ABDE, ABFR, ABES, ABOL, TI
Abstract (contains AB, ABDE, ABES, ABFR, ABOL) 1,2)	/AB		AB, ABDE, ABES, ABFR, ABOL
Application Country	/AC	S WO/AC AND (INLAND(W)STEEL)/PA	AI
Filing Country for PCT Application	/AC.WO	S FR/AC.WO	AI
Application Date	/AD	S 19840705/AD	AI
Application Kind Code Text	/AIT	S MWA/AIT	AIT
Application Kind Code	/AK	S WOA/AK	AI, AIT
Abstract Language (ISO code and text)	/AL	S DUTCH/AL	ALL, ALLO, IMAX, MAX, MAXO
Accession Number	/AN	S 12345678/AN	AN
Application Number	/AP	S ZW1981-215/AP	AI
Application Year	/AY	S 1988/AY AND SIEMENS/PAS	AI
Citation Category	/CAT	S X/CAT	REN, REP
Changes (Indicator for the changes in the last update)	/CHG	S EPC C/CHG	CHG
Data Availability	/DAV	S NOT-PRINTED-WITH-GRANT/DAV	DAV
Designated States	/DS	S W JP/DS	DS
Document Type (code and text)	/DT (/TC)	S U/DT AND UNILEVER/PAS	DT
Entry Date	/ED	S L1 AND ED>1 JAN 2007	ED
Entry Date New Patent Family	/EDF	S 20070321/EDF	EDF
Entry Date new publication and/or New Legal Status	/EDLS	S EDLS=20070419	not displayed
Entry Date Patent	/EDP	S 20061130	EDP
Entry Date Priority	/EDPR	S 20070401-20070429/EDPR	PRAI
European Patent Classification	/EPC	S A01B0015-20/EPC	EPC
EPC, Keyword Terms	/EPC.KW	S D2/EPC.KW	EPC
Entry Week (INPADOC)	/EW	S 199801/EW	EW
Field Availability	/FA	S L7 AND DS/FA	FA
Filing Details	/FDT	S DEC3D6/FDT	FDT
IPC (contains ICM and ICS), Version 1-7	/IC	S C07H019-16/IC	IC
IPC, Version from IC	/IC.VER	S 7/IC.VER	IC.VER, IC
IPC, Additional (supplementary) Version 1-7	/ICA	S A61K037-64/ICA	ICA
IPC, Index (complementary) Version 1-7	/ICI	S (C12P019-40(L)C12R001:465)/ICI	ICI
IPC, Main, Version 1-7	/ICM	S C23C001-08/ICM	ICM
Indexing Codes (EPO)	/ICO	S K61M/ICO	ICO
IPC, Secondary	/ICS	S C12P019-40/ICS	ICS
Indeling der Techniek (EPO/NL)	/IDT	S 12C2PE4/IDT	IDT
Inventor	/IN (/AU)	S NICKOLA RICHARD?/IN	IN

- 1) In addition to right truncation, simultaneous left and right truncation are available in this field. At least 4 characters need to be used for the length of the stem.
- 2) This field is available for selected countries and patent publications (see HELP CONTENT)
- 3) Numeric search field that may be searched using numeric operators or ranges.
- 4) Either STN format or Derwent format may be used.
- 5) Available since 2006.
- 6) Available since week 200639
- 7) Search in IPC8 format also available.

BIBLIOGRAPHIC SEARCH AND DISPLAY FIELDS (continued)

Search Field Name	Search Code	Search Examples	Display Code
Inventor Address	/INA	S HEIDELBERG/INA	INA
Inventor Address, Country	/IN.CNY	S GB/IN.CNY	INS
Inventor INPADOC Standard	/INS	S AGARWAL S?/INS	INS
International Patent Classification (contains ICM, ICS, ICA, ICI, IPCI, IPCR)	/IPC	S H05B0006-36+NT/IPC S H05B0006-36-H05B0006-44/IPC	IC, ICA, ICI, ICM, ICS, IPCI, IPCR
IPC, Action Date	IPC.ACD	S 13 JAN 2006/IPC.ACD	IPC.TAB
IPC, Keyword Terms	IPC.KW	S INITIAL/IPC.KW	IPC.TAB
IPC, Version from IPC	IPC.VER	S 200601/IPC.VER	IPC.TAB
Language (ISO code and text)	/LA	S DE/LA	LA
Language of Filing (ISO code and text)	/LAF	S FR/LAF	LAF
National Patent Classification	/NCL	S U1S1002/NCL	NCL
Patent Assignee 8)	/PA (/CS)	S INLAND STEEL/PA S BROWN WILLIAMSON/CS	PA
Patent Assignee Address	/PAA	S US/PAA AND (ATOMIC(S)ENERGY)/PAS	PAA
Patent Assignee, Country	/PA.CNY	S GB/PA.CNY	PAS
Patent Assignee INPADOC Standard	/PAS	S INLAND STEEL CO?/PAS S (BROWN(S)TOBACCO)/PAS	PAS
Patent Country (WIPO code and text)	/PC	S DE/PC AND IBM/PAS AND 1988/PY	PI
Publication Date 3)	/PD	S 19990104/PD	PI
Patent Information Publication Type	/PIT	S DECO GRANTED?/PIT	PIT
Patent Kind Code	/PK	S ZWA/PK	PI
Patent Number 4)	/PN	S FI990202U/PN	PI
Priotiy Kind Text	/PRAIT	S ARA PATENT APPLICATION/PRAIT	
Priority Country (WIPO code and text)	/PRC	S JP/PRC AND 19880101/PRD	PRAI
Filing Country for PCT Priorities (WIPO code and text)	/PRC.WO	S DE/PRC.WO	PRAI
Priority Date 3)	/PRD	S JP/PRC AND 19880101-19880331/PRD S 1980US-0167554/PRD	PRAI
Priority Kind Code	/PRK	S DEA1/PRK	
Priority Number 4)	/PRN	S US1990-169937/PRN	PRAI
Priority Year 3)	/PRY	S 1998/PRY AND US/PRC	PRAI
Priority Year, First 3)	/PRYF	S GB/PC AND 1998/ PRYF	PRAI
Publication Year 3)	/PY	S 1999/PY	PI
Referenced Non-Patent Literature	/REN	S MAYER/REN	REN
Non-Patent Literature XP-Document Number	/REXP	S XP002235691/REXP	REXP
Referenced Patent Number	/RPN	S EP1234567/RPN	REP
Origin of Citation	/SRT	S SEA/SRT	REN, REP REXP
Patent Status	/STA	S GRANTED/STA	STA
Title 1)	/TI	S (APPARAT? (S) SMOKE (S) FILTER#)/TI	TI
Title Language (ISO code and text)	/TL	S EN/TL S ENGLISH/TL	TL
Update Date 3)	/UP	S L1 AND UP>20070102	UP
Update Date of the BIB fields 3)	/UPBB	S L1 AND UPBB>20070222	UPALL
Update Date Classifications 3)	/UPCC	S L1 AND UPCC>20070222	UPALL
Update Date Patent Family (All Updates) 3)	/UPFA	S 20070329/UPFA	UPALL
Update Date Patent Family Bibliographic 3)	/UPFB	S 20070215/UPFB	UPALL
Update Date Patent Family Bibliographic 3)	/UPFD	S 20070215/UPFD	UPALL
Update Date New Publication and/or Legal Status Changes 3)	/UPFE	S 20070321/UPFE	UPALL

1) In addition to right truncation, simultaneous left and right truncation are available in this field. At least 4 characters need to be used for the length of the stem.

4) Either STN format or Derwent format may be used.

8) Search with implied (S) proximity is available in this field.

BIBLIOGRAPHIC SEARCH AND DISPLAY FIELDS (continued)

Search Field Name	Search Code	Search Examples	Display Code
Update Date Patent Family Legal Status 3)	/UPFL	S 20070321/UPFL	UPALL
Update Date Patent Family Publication Level 3)	/UPFP	S 20070222/UPFP	UPALL
Update Date Legal Status 3)	/UPLS	S UPLS=20070222	LS, LSUP
Update Date All Patent Changes 3)	/UPM	S L1 AND 20070222/UPM	not displayed
Update Week (INPADOC Week) 3)	/UW	S UW=200641	UW

3) Numeric search field that may be searched using numeric operators or ranges.

LEGAL STATUS SEARCH AND DISPLAY FIELD CODES

Search Field Name	Search Code	Search Examples	Display Code
Entry Date new publication and/or New Legal Status 1)	/EDLS	S EDLS=FEB 2007	not displayed
Entry Week Legal Status	/EWLS	S 200641-200642/EWLS	LS2
Legal Status Represen./Agent	/LSAG	S (LORENZ AND PHILIPPS)/LSAG	LS
Legal Status Basic Index (contains legal status agent (LSG), legal status free format text (LSFT), legal status inventor (LSIN), legal status patent opponent (LSOP), and legal status patent assignee (LSPA) fields)	/LSBI	S LASER?/LSBI S ANACOMP/LSBI S OPPOSITE/LSBI	LS
Legal Status Code (code and text)	/LSC	S EP111L/LSC	LS
Legal Status Code Category	/LSC2	S NIF/LSC2	LS
Legal Status Code Country (WIPO code and text)	/LSCC	S BE/LSCC	LS
Legal Status Indicator	/LSCI	S POSITIVE/LSCI	LS
Legal Status Country (WIPO code and text)	/LSCY	S UNITED KINGDOM/LSCY	LS
Legal Status Date INPADOC GAZETTE 1)	/LSD	S LSD=JAN 2002	LS
Legal Status Date in Force Country 1)	/LSDF	S LSDF=20050109	LS
Legal Status Designated States (WIPO code and text)	/LSDS	S AU/LSDS S AUSTRALIA/LSDS	LS
Legal Status Free Format Text	/LSFT	S TELECOMMUNICATION/LSFT	LS
Legal Status IPC	/LSIC	S 41J320/0/LSIC	LS
Legal Status Patent Inventor	/LSIN	S MAYER, BERND/LSIN S (MAYER(S)BERND)/LSIN	LS
Legal Status Patent Opponent	/LSOP	S SIEMENS AG/LSOP	LS
Legal Status Patent Assignee	/LSPA	S (MAN(S)CERAMICS)/LSPA	LS
Legal Status Publication Country (WIPO code and text)	/LSPC	S CA/LSPC S CANADA/LSPC	LS
Legal Status Publication Date 1)	/LSPD	S LSPD=JAN 1998	LS
Legal Status Publication Kind Code	/LSPK	S ES00/LSPK	LS
Legal Status Payment Year 1)	/LSPMY	S 18/LSPMY	LS
Legal Status Publication Number	/LSPN	S EP200212/LSPN	LS
Legal Status Publication Year 1)	/LSPY	S 1999-2000/LSPY	LS
Legal Status SPC Number	/LSSPC	S EU/1/00/137/001/LSSPC	LS
Legal Status SPC, Extension Date 1)	/LSSPC.EX	S 20010910/LSSPC.EX	LS
Legal Status SPC, Filing Date 1)	/LSSPC.FD	S 19950101-19961231/LSSPC.FD	LS
Legal Status SPC, Expiry Date 1)	/LSSPC.XD	S LSSPC.XD>2005	LS
Legal Status Code Text	/LSTX	S CORRECTION/LSTX	LS
Update Legal Status 1)	/UPLS	S 20040806/UPLS	LS, LSUP

1) Numeric search field that may be searched using numeric operators or ranges.

Super Search Fields 1)

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group 2)	/APPS	/AP,/PRN	S DE1984-3400052/APPS S 1984DE-3400052/APPS	AI, PRAI
Inventor Group	/INSS	/IN, /INS, /LSIN	S MEIE/INSS	IPC
Patent Assignee Group	/PASS	/PA, /PAS, /LSPA	S MEIER/PASS	PI
Patent Number Group 2)	/PATS	/PN, /RPN	S WO1989004114/PATS	PI, REP
Patent Countries	/PCS	/PC,/DS	S DE/PCS	PI, DS

- 1) Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.
- 2) Either STN format or Derwent format may be used.

IPC Thesaurus

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1-8, use the field code followed by the edition number, e.g., /IPC2 for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

Code	Content	Examples
ADVANCED (ADV)	Advanced Level Codes for the Core Level IPC Code	E A61K0066-02+ADVANCED/IPC
ALL	All Associated Terms (BT, SELF, NT, RT)	E C01C003-00+ALL/IPC
BRO (MAN)	Complete Class	E C01C+BRO/IPC
BT	Broader Term (SELF, BT)	E C01F001-00+BT/IPC
BTn	Broader Term (SELF, BT) up to the next n levels (n =1,2,...)	E C01F001-21+BT2/IPC
CORE (COR)	Core Codes for the Advanced Level IPC Code	E G08C0019-22+CORE/IPC
ED	Complete title of the SELF term and IPC manual	E C01F001-00+ED/IPC
HIE	Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT)	E C011003-00+HIE/IPC
INDEX	Complete title of the SELF term	E C01F001-00+INDEX/IPC
KT	Keyword Term (catchwords) (SELF, KT)	E CYANOGEN+KT/IPC
NEXT	Next Classification	E C01C001-00+NEXT5/IPC
NT	Narrower Terms (SELF, NT)	E C01C+NT/IPC
NTn	Narrower Terms (SELF, NT) down to the next n levels (n =1,2,...)	E C01C+NT3/IPC
PREVn	Previous Classification (n =1,2,...)	E C01C001-12+PREV10/IPC
RT (SIB)	Related Terms (SELF, RT)	E C01C003-20+RT/IPC
TI	Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C01F001-00+TI/IPC

DISPLAY AND PRINT FORMATS

Any combination of display fields and formats may be used to display or print answers. Multiple codes must be separated by commas or spaces, e.g. 'D L1 1-5 TI PI'. The fields are displayed or printed in the order requested.

You can combine all display fields and all display formats with the qualifier .M to display the content for all publications of a record.

You can combine all display fields and all display formats with the qualifier .F to display the content for all family members (will be charged as a family display).

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH in order to use the HIT, KWIC, and OCC formats.

More information about display fields for specific types of information is available by typing one of the following 'HELP' commands at an arrow prompt (=>) in the INPADOCDB database:

INPADOCDB

HELP DFIELDS	-	lists all valid custom formats
HELP EFIELDS	-	lists all selectable fields
HELP FORMATS	-	lists valid predefined formats
HELP SRTFIELDS	-	lists valid sort fields

Format	Definition	Examples
AB	Abstract in English	D AB
ABDE	Abstract in German	D ABDE
ABES	Abstract in Spanish	D ABES
ABFR	Abstract in French	D ABFR
ABOL	Abstract in Other Language	D ABOL
AI	1) Application Information	D AI
AIT	Application Kind Code Text	D AIT
AN	Accession Number	D AN
APPS	1) Application Number Group	D APPS
CHG	Changes (Indicator for changes in the last update)	D CHG
DAV	Data Availability	D DAV
DS	Designated States	D DS
DT (TC)	Document Type	
ED	Entry Date	D 1-5 ED UP
EDP	Entry Date Patent	D EDP
EPC (ECLA)	European Patent Classifications (EPC, ICO, IDT)	D EPC
EW	Entry Week	
FA	Field Availability	
FDT (PT)	Filing Details	
FN	Family Number	D FN
IC	International Patent Classification (ICM, ICS)	
ICA	IPC, Additional (supplementary)	
ICI	IPC, Index (complementary)	
ICM	IPC, Main	D ICM L7
ICS	IPC, Secondary	
IN	Inventor	
INA (IN.CNY)	Inventor Address	
INS	Inventor INPADOC Standard	
IPCI	IPC, Initial	D IPCI
IPCR	IPC, Reclassified	D IPCR
LA	Language	
LAF	Language of Filing	D LAF
NCL	National Patent Classification	
PA (CS)	Patent Assignee	D PA TI 1-10
PAA	Patent Assignee Address	
PAS	Patent Assignee INPADOC Standard	
PI (PN)	1) Patent Information	
PIT	Patent Information Publication Type	D PIT 1-5
PRAI (PRN)	1) Priority Information	
PRAIT	Priority Kind Text	D PRAIT
REC (RE.CNT)	Reference Count	D REC
REN (NPL)	Referenced Non-Patent Literature	D REN
REP	Referenced Patents	D REP
REXP	Non-Patent Literature XP-Document Number	D REXP
STA	Status	D STA
TI	Title	D TI
TL	Title Language	D TL
UP	Update Date	
UW	Update Week (INPADOC Week)	
ABS	AN, AB, ABDE, ABES, ABFR, ABOL	D ABS
ALL	1) BIB, all Abstracts, IND, FA, CHG	D ALL 6
ALLO	ALL, for previous update	
IALL	1) ALL, indented with text labels	D IALL L3 7
BIB	1) AN, FN, ED, EW, UP, UW, TI, TL, IN, INS, INA, PA, PAS, PAA, DT, LA, LAF, PI, PIT, DAV, STA, DS, XS, AI, AIT, PRAI, PRAIT, REC (The default format is BIB.M)	
IBIB	1) BIB, indented with text labels	D 5 IBIB
IND	AN, ED, EW, UP, UW, IPC, EPC, ICO, IDT, NCL	D L5 IND

1) By default, patent numbers, application and priority numbers are displayed in STN format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN format, enter SET PATENT STN.

DISPLAY AND PRINT FORMATS (continued)

Format	Definition	Examples
IPC IPC.TAB LS LS2 LSUP MAX IMAX MAXO PATS RE SCAN STD TRIAL (TRI,FREE, SAMPLE, SAM)	ICM, ICS, ICA, ICI, IPCR, IPCI IPC, IPC.KW, IPC.ACD, IPC.VER, Tabular display AN, UPLS, Legal Status Legal Status, detailed version with display headers Last LS Update 1) ALL.M plus all Abstracts, PRAIT, RLI, AIT, FDT, LS 1) MAX, indented with text labels MAX, with original data in UTF-8 characters Patent Number Group (PI, REP) Cited References (REP, REXP, REN) 2) TI latest publication (random display without answer number) BIB, IND TI, FA	D IPC.TAB D LS2 D IMAX D MAX D PATS D RE D SCAN D TRIAL 5
HIT KWIC OCC	Hit-term(s) and field(s) Up to 50 words before and after hit-term(s) (KeyWord-In-Context) Number of occurrences of hit-term(s) and field(s) in which they occur	D HIT D KWIC D OCC

- 1) By default, patent numbers, application and priority numbers are displayed in STN format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN format, enter SET PATENT STN.
- 2) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

FAMILY DISPLAY AND PRINT FORMATS

Format	Definition	Examples
TIPI.F PILS.F BIBLS CFAM DFAM EFAM FAM FAM2 FFAM FFAM.PC IFAM LFAM MFAM UPALL	TI + LS for all patent family members 1) PI + LS for all patent family members 1) BIB + LS for all patent family members 1) Condensed FAM with only PI in the table 1,2) FAM, delimited for post processing 1) FAM, but the priority information constitutes the header 1) AN, table of patent family information 1) AN, table of Patent Family information, another order 1) STD + LS for each member of the family 1,3) FFAM for a specified country only 1) Combines indented FAM and IMAX.F 1) AN, PI, LSUP for all members of a patent family 1) MAX for each family member Table of update dates UPBB, UPCC, EDP, EDF, UPFD, UPFP, UPFL	D TIPI.F D PILS.F D BIBLS D CFAM D DFAM D EFAM D FAM D FAM2 D FFAM D FFAM.PC D IFAM D LFAM D MFAM D UPALL

- 1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
- 2) SET LINE 100 is recommended.
- 3) PC = AT BE CA CH CN DE DK EP ES FI FR GB JP KR NO RU SE US WO

FAMILY DISPLAY AND PRINT FORMATS – Weekly SDI

Format	Definition	Examples
FFAMED 1)	STD for new publications and/or LSUP for each updated family	D FFAMED
FFAMED.PC 1,2)	FFAMED for a specific country only	D FFAMED.PC
FFAMUP 1)	STD + LS for each updated family	D FFAMUP
FFAMUP.PC 1,2)	FFAMUP for a specific country only	D FFAMUP.PC
IFAMED 1)	Indented FFAMED plus patent family table	D IFAMED
IFAMUP 1)	Indented FFAMUP plus patent family table	D IFAMUP
LFAMUP 1)	AN, PI, LSUP for all updated members of a patent family	D LFAMUP
LFAMUP.PC 1,2)	LFAMUP for a specific country only	D LFAMUP.PC

- 1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
 2) PC = AT BE CA CH CN DE DK EP ES FI FR GB JP KR NO RU SE US WO

FAMILY DISPLAY AND PRINT FORMATS – Monthly SDI

Format	Definition	Examples
FFAMED4 1)	STD for new publications and/or LSUP for each updated family	D FFAMED4
FFAMUP4 1)	STD + LS for each updated family	D FFAMUP4
IFAMED4 1)	Indented FFAMED4 plus patent family table	D IFAMED4
IFAMUP4 1)	Indented FFAMUP4 plus patent family table	D IFAMUP4
LFAMUP4 1)	AN, PI, LSUP for all updated members of a patent family	D LFAMUP4

- 1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.

SORTING WITHIN THE PATENT FAMILY DISPLAY FORMATS

Format	Default sorted by
FAM	PRN (Priority Number)
DFAM	PRN (Priority Number)
EFAM	PRN (Priority Number)
FFAM	PN (Patent Number) of the highest level
LFAM	PN (Patent Number) of the highest level
CFAM	AP (Application Number)

SORTING WITHIN THE PATENT FAMILY DISPLAY FORMATS

You can define the sort parameter in family display formats. Depending on the formats used, options are priority date (.PRD), publication date (.PD), patent number (.AP), application date (.AD). The following combinations are available.

Format	Sorted by Parameter
FAM.PRD	Priority Date
CFAM.PD	Publication Date
DFAM.PRD	Priority Date
DFAM.AP	Application Number
DFAM.AD	Application Date
DFAM.PN	Patent Number
DFAM.PD	Patent/Publication Date
EFAM.PRD	Priority Date

SELECT, ANALYZE, AND SORT CODES

The SELECT command is used to create E-numbered or L-numbered lists of terms taken from the specified field(s) in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphanumeric (A) or numeric (N) order of the specified field(s).

Definition	Code	Analyze/ Select 1)	Sort
Abstract in English	AB	x	A
Abstract in German	ABDE	x 2)	A
Abstract in Spanish	ABES	x 2)	A
Abstract in French	ABFR	x 2)	A
Abstract in Other Language	ABOL	x 2)	A
Application Country	AC	x	A
Application Date	AD	x	N
Application Information	AI	x 3)	A
Application Kind Code Text	AIT	x	A
Application Kind Code	AK	x	A
Application Number	AP	x 3)	A
Application Number Group	APPS	x 3,4)	-
Application Year	AY	x	N
Changes (Indicator for the changes in the last update)	CHG	x	-
Designated State	DS	x	-
Document Type	DT (TC)	x	A
Entry Date	ED	x	-
Entry Date Patent	EDP	x	-
European Patent Classification	EPC (ECLA)	x	A
Entry Week	EW	x	-
International Patent Classification	IC	x	-
IPC, Additional (supplementary)	ICA	x	A
IPC, Index (complementary)	ICI	x	A
IPC, Main	ICM	x	A
IPC, Secondary	ICS	x	A
Indexing Codes (EPO)	ICO	x	A
Indeling der Techniek (EPO/NL)	IDT	x	A
Inventor	IN (AU)	x	A
Inventor Address, Country	IN.CNY	x	A
Inventor Address	INA	x	A
Inventor INPADOC Standard	INS	x	A
International Patent Classification	IPC	x	A
IPC, Advanced Level Symbols	IPC.A	x 5)	-
IPC, Advanced Level Symbols for Invention	IPC.AI	x 5)	-
IPC, Core Level Symbols	IPC.C	x 5)	-
IPC, Core Level Symbols for Invention	IPC.CI	x 5)	-
Pre-IPC8 Symbols from the ICM and first IPC8 values from 2006 onwards	IPC.F	x 5)	A
IPC, Initial	IPCI	x 5)	-
IPC, Reclassified	IPCR	x 5)	-
Language	LA	x	A
Language of Filing	LAF	x	A
Legal Status Representative/Agent	LSAG	x	-
Legal Status Code	LSC	x	-

- 1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
- 2) Appends /AB to the terms created by SELECT.
- 3) SELECTed and SORTed application, priority and patent numbers are in the format set by the Messenger SET PATENT command, either DERWENT or STN.
- 4) Selects or analyzes AP, PRN, and appends /APPS to the terms created by SELECT.
- 5) Appends /IPC to the terms created by SELECT.

SELECT, ANALYZE, AND SORT CODES (continued)

Definition	Code	Analyze/ Select 1)	Sort
Legal Status Code Category	LSC2	x	-
Legal Status Code Country	LSCC	x	-
Legal Status Date INPADOC GAZETTE	LSD	x	-
Legal Status Free Format Text	LSFT	x	-
Legal Status IPC	LSIC	x	-
Legal Status Patent Inventor	LSIN	x	-
Legal Status Patent Opponent	LSOP	x	-
Legal Status Patent Assignee	LSPA	x	-
Legal Status Publication Country	LSPC	x	-
Legal Status Publication Date	LSPD	x	-
Legal Status Payment Year	LSPMY	x	-
Legal Status Publication Number	LSPN	x	-
Legal Status SPC Number	LSSPC	x	-
Legal Status SPC, Extension Date	LSSPC.EX	x	-
Legal Status SPC, Filing Date	LSSPC.FD	x	-
Legal Status SPC, Expiry Date	LSSPC.XD	x	-
National Patent Classification	NCL	x	A
Occurrence Count of Hit Terms	OCC	-	N
Patent Assignee	PA (CS)	x	A
Patent Assignee, Country	PA.CNY	x	A
Patent Assignee Address	PAA	x	A
Patent Assignee INPADOC Standard	PAS	x	A
Patent Number Group	PATS	x 6)	A
Patent Country	PC	x	A
Publication Date	PD	x	N
Patent Information Publication Type	PIT	x	A
Patent Kind Code	PK	x	A
Patent Number	PN (PI)	x 3)	A
Priority Kind Text	PRAIT	x	A
Priority Country	PRC	x	A
Priority Date	PRD	x	N
Priority Kind Code	PRK	x	A
Priority Number	PRN (PRAI)	x 3)	A
Priority Year	PRY	x	N
Priority Year, First	PRYF	x 7)	A
Publication Year	PY	x	N
Referenced Patents	REP	x	A
Referenced Non-Patent Literature	REXP	x	A
Title	TI	x (default)	A
Update Date	UP	x	-
Update Week	UW	x	-

- 1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
- 3) SELECTed and SORTed application, priority and patent numbers are in the format set by the Messenger SET PATENT command, either DERWENT or STN.
- 6) Selects or analyzes /PN, /RPN with /PATS appended to the terms created by SELECT.
- 7) SELECT or ANALYZE HIT are not valid with this field.

UPDATE CODES (for SDI also)

Update codes or entry dates associated with records

Field Name	Search Code	Search Examples	Display Code
Entry Date	/ED	S L1 AND ED>DEC 2006	ED
Entry Date + Legal Status Update	/EDLS		
Entry Date Patent	/EDP	S 20061026/EDP	EDP, UPALL
Entry Date Priority	/EDPR		PRAI
Update Date	/UP	S 20070102/UP	LS
Update Legal Status	/UPLS	S 20070222/UPLS	LS
All updates of a record	/UPM	S 20070215/UPM	not displayed

Update codes or entry dates associated with patent families (1,2)

Field Name	Search Code	Search Examples	Display Code
Entry Date new patent family	/EDF	S L1 AND EDF>21 MAR 2007	UPALL
All changes in a patent family	/UPFA	S L1 AND 20070329/UPFA	not displayed
Any change of a bibliographic element in a patent family	/UPFB	S L1 AND 20070215/UPFB	UPALL
Entry of a new database record (document) into a patent family (level 1)	/UPFD	S L1 AND 20070215/UPFD	UPALL
Entry of a new publication and changes in legal status	/UPFE	S L1 AND 20070321/UPFE	not displayed
Any change of a legal status in a patent family	/UPFL	S L1 AND 20070321/UPFL	UPALL
Entry of a new publication level into a patent family	/UPFP	S L1 AND 20070222/UPFP	UPALL

1) Available since February 2007.

2) Special display formats available for monitoring patent families weekly.

SAMPLE RECORDS

DISPLAY MAX

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AN      24180089 INPADOCDB UP 20061123
FN      13550763
TI      Verfahren und Vorrichtung zum Schneiden eines beschichteten Blattes.
        Coated sheet cutting method and apparatus.
        Procédé et appareil pour la coupe d'une feuille revêtue.
TL      German; English; French
IN      KAWAI, HIROKAZU
INS     KAWAI HIROKAZU, JP
PA      FUJI PHOTO FILM CO., LTD.
PAS     FUJI PHOTO FILM CO LTD, JP
DT      Patent
PI      EP 1488896          A1 20041222  English
PIT     EPAL APPLICATION PUBLISHED WITH SEARCH REPORT
DAV     20041222  examined-printed-without-grant
STA     PRE-GRANT PUBLICATION
DS      R:                DE FR GB
AI      EP 2004-13971      A   20040615
AIT     EPA Patent application
PRAI    JP 2003-174783     A   20030619  (JPA)
        JP 2003-174784     A   20030619  (JPA)
PRAIT   JPA Patent application
REP     JP 2001138285     A   (SEA, npl, Cat: Y)
        JP 06168444       A   (SEA, npl, Cat: Y)
REXP    XP000510813      (SEA, Cat: A)
REN     (1) PATENT ABSTRACTS OF JAPAN vol. 2000, no. 22, 9 March 2001
    
```

INPADOCDB

(2001-03-09) & JP 2001 138285 A (SONY CORP), 22 May 2001 (2001-05-22)

(SEA, Cat: Y)

(2) PATENT ABSTRACTS OF JAPAN vol. 0185, no. 05 (P-1803), 21 September 1994 (1994-09-21) & JP 6 168444 A (MATSUSHITA ELECTRIC IND CO LTD), 14 June 1994 (1994-06-14) (SEA, Cat: Y)

(3) KLEIN H: "LANGSSCHNEIDEN VON BAHNFORMIGEN MATERIALIEN DER KREISMESSER-SCHERENSCHNITT UND SEINE OPTIMALE EINSTELLUNG FUR DAS LANGSSCHNEIDEN BAHNFORMIGER MATERIALIEN (TEIL 3)" COATING, VERLAG COATING THOMAS & CO, CH, vol. 28, no. 5, 1 May 1995 (1995-05-01), pages 176-179, XP000510813 ISSN: 0590-8450 (SEA, Cat: A)

IC.V

7

ICM

B26D001-24

IPCR

B26D0001-24 [I,A]; B26D0007-26 [N,A]
B26D0001-01 [I,C*]; B26D0007-26 [N,C*]

EPC

B26D0001-24B

ICO

L26D0007:26C2

AB

A discoid lower blade and a discoid upper blade, having a sharper knife angle compared with that of the lower blade, are arranged such that rotational axes thereof are parallel to each other, and portions of the blades overlap one another in the direction that the rotational axes extend. A sheet with a coating layer on one side is fed through and shear-cut between the upper and lower blades in the direction perpendicular to the rotational axes, with the surface of the sheet opposite the coating layer in contact with a periphery of the lower blade while the blades are rotated. When the sheet is shear-cut, a contact start position, where contact between the sheet and the upper blade starts, is positioned upstream in the feed direction of the sheet but outside a contacting area of the sheet, where the sheet contacts the periphery of the lower cutting blade. Alternatively, the contact start position starts within the contacting area and an overlap between a part of the upper cutting blade and a part of the lower cutting blade is maintained less than 1.5 mm. <IMAGE>.

AL

English

AS

EPO

FA

AB; AI; AN; DAV; DS; DT; EPC; ICM; ICO; IN; INS; IPC; IPCR; LA; PA; PAS; PI; PIT; PRAI; REN; REP; REXP; TI

AN

24180089 INPADOCDB UP 20061005

TI

Verfahren und Vorrichtung zum Schneiden eines beschichteten Blattes.
Coated sheet cutting method and apparatus.
Procede et appareil pour la coupe d'une feuille revetue.

TL

German; English; French

IN

KAWAI, HIROKAZU

INS

KAWAI HIROKAZU, JP

PA

FUJI PHOTO FILM CO., LTD.

PAS

FUJI PHOTO FILM CO LTD, JP

DT

Patent

PI

EP 1488896 B1 20061004 English

PIT

EPB1 PATENT SPECIFICATION

DAV

20061004 printed-with-grant

STA

GRANTED

DS

R: DE FR GB

AI

EP 2004-13971 A 20040615

AIT

EPA Patent application

PRAI

JP 2003-174783 A 20030619 (JPA)

JP 2003-174784 A 20030619 (JPA)

PRAIT

JPA Patent application

IPCI

B26D0001-24 [I,A]; B26D0001-01 [I,C*]

IPCR

B26D0007-26 [N,A]
B26D0007-26 [N,C*]

EPC

B26D0001-24B

ICO

L26D0007:26C2

FA

AI; AN; DAV; DS; DT; EPC; ICO; IN; INS; IPC; IPCI; IPCR; LA; PA; PAS; PI; PIT; PRAI; TI

LEGAL STATUS

AN

24180089 INPADOCDB

INPADOCDB

20041222 EPAK + DESIGNATED CONTRACTING STATES:
 EP A1
 AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IT LI LU
 MC NL PL PT RO SE SI SK TR

20041222 EPAX + EXTENSION OF THE EUROPEAN PATENT TO
 AL HR LT LV MK

20050803 EP17P + REQUEST FOR EXAMINATION FILED
 20050603

20050914 EPAKX EXA Examination, Search Report
 + PAYMENT OF DESIGNATION FEES
 DE FR GB

20061004 EPAK + DESIGNATED CONTRACTING STATES:
 EP B1
 DE FR GB

20061004 EPREG REFERENCE TO A NATIONAL CODE
 GBFG4D + GB: EUROPEAN PATENT GRANTED
 200641

20061116 EPREF CORRESPONDS TO:
 DE 602004002620 P 20061116
 200646

20070314 EPRAP2 PATENT OWNER REASSIGNMENT (CORRECTION)
 FUJIFILM CORPORATION
 CHG Change of Owner, Inventor, Applicant
 200711.....20070315

20070411 EPREG REFERENCE TO A NATIONAL CODE
 GB732E GB: PROCEEDING UNDER SECTION 32 PATENTS ACT 1977
 CHG Change of Owner, Inventor, Applicant
 200716.....20070419

20070420 EPET + FR: TRANSLATION FILED
 200719.....20070510

DISPLAY FAM

PATENT FAMILY INFORMATION
 AN 24180089 INPADOCDB

+-----PRAI-----+			+-----AI-----+		
JP 2003-174783	A	20030619	CN 2004-10059710	A	20040617
			DE 2004-602004002620	T	20040615
			EP 2004-13971	A	20040615
			JP 2003-174783	A	20030619
			US 2004-868808	A	20040617
JP 2003-174784	A	20030619	CN 2004-10059710	A	20040617
			DE 2004-602004002620	T	20040615
			EP 2004-13971	A	20040615
			JP 2003-174784	A	20030619
			US 2004-868808	A	20040617
+-----AI-----+			+-----PI-----+		
CN 2004-10059710	A	20040617	CN 1572446	A	20050202
DE 2004-602004002620	T	20040615	DE 602004002620	D1	20061116
EP 2004-13971	A	20040615	EP 1488896	A1	20041222
			EP 1488896	B1	20061004
JP 2003-174783	A	20030619	JP 2005007524	A	20050113
JP 2003-174784	A	20030619	JP 2005007525	A	20050113
US 2004-868808	A	20040617	US 20040255743	A1	20041223

2 priorities, 6 applications, 7 publications

DISPLAY ALL

AN 51399732 INPADOCDB UP 20070426 UW 200717
 FN 34407383
 TI Neck fastening for mechanical line-fastening of insulating material and sealing tracks on flat roofs consists of rail with holes and fastenings formed from screws anchored onto rail bottom and supported with head on rail.
 Kehlbelegung fuer die mechanische Linienbefestigung von Daemmmaterialien und Abdichtungsbahnen auf Flachdaechern.

TL English; German
 PA HARALD ZAHN GMBH
 PAS ZAHN HARALD GMBH, DE
 DT Patent
 PI DE 102005022624 A1 20061123
 PIT DEAL DOC. LAID OPEN (FIRST PUBLICATION)
 DAV 20061123 unexamined-printed-without-grant
 STA PRE-GRANT PUBLICATION
 AI DE 2005-102005022624 A 20050517
 AIT DEA Patent application
 PRAI DE 2005-102005022624 A 20050517 (DEA)
 PRAIT DEA Patent application
 IPCI E04D0005-14 [I,A]; E04B0001-74 [I,A]; E04D0003-36 [I,A]; E04D0005-00 [I,C*]; E04B0001-74 [I,C*]; E04D0003-36 [I,C*]

AB Neck fastening consists of a rail with holes made in the rail bottom and individual fastenings. Fastenings are each formed from a screw (1) which is put in the rail base, supported with its head (3) on the rail and which cuts with its end into the roof bottom or juts into a wall plug anchored into the roof base. From both sides of the hole on the rail narrow positioning edges or noses protrude on which the underside of the screw head lies. When its clamping force is held steady suspended see-saw like between its positioning edges or noses, the rail lies on the underside of the screw head.

AL English
 AS transcript
 FA AB; AI; AN; DAV; DT; IPC; IPCI; PA; PAS; PI; PIT; PRAI; TI
 CHG TI A